Editor-in-Chief's Message for the Inaugural Issue

*W*arm Welcome to the readers and authors of IEEE Reliability Digest!

It is my pleasure to introduce the inaugural issue of IEEE Reliability Digest. In this special issue on trustworthy computing and cybersecurity, Area Editor Wen-Guey Tzeng brings you the recent progress on this cutting edge technology. Dr. Wen-Guey Tzeng is an expert in the field of trustworthy computing and cryptography. Hope you all enjoy reading this very interesting issue.

IEEE Reliability Digest is a peer-reviewed online magazine of the IEEE Reliability Society, published quarterly in February, May, August, November, respectively. It addresses reliability, security and related assurance topics, including recent innovations and advancements of emerging hot topics as well as new techniques and methodologies, experiences and practices, case studies and benchmarks. Its scope covers but is not limited to cybersecurity, software assurance, intrusion detection, computer and network security, PHM (Prognostics and Health Management), reliability science for advanced materials and devices, big data, IoT (Internet of Things), mobile and cloud computing.

As the Editor-in-Chief, I would like to express my sincere gratitude to the area editors, authors and reviewers who devoted their time and effort in launching the first issue of Reliability Digest. The online magazine is intended to serve as a forum for scholars to exchange their opinions.

You are very welcome to submit your articles to Reliability Digest. Only with your support and assistance can Reliability Digest better serve our community. Your comments and feedback will be greatly appreciated.

Enjoy Reading.

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